

Front End Electronics (FEE 2014)

Friday, 23 May 2014

Advanced CMOS and Extreme Environments Session II - Energy Sciences Building (10:15 - 11:30)

-Conveners: Gary Varner

time	[id] title	presenter
10:15	[40] Radiation Damage Tests at 1 Grad Dose on 65 nm CMOS Transistors	BARBERO, Marlon Benoit
10:40	[41] LArASIC4 Noise Results in Liquid Argon Long Drift Tests	Dr KRESLO, Igor
11:05	[42] CMOS Lifetime at 300K and at 77K	LI, Shaorui